

IN THE CLAIMS:

Please substitute the following claims for the same-numbered claims in the application:

1. (Previously Presented) A system for calculating semiconductor product costs at a fabricator comprising:
 - a storage medium including a database of historical costs and historical critical gate dimensions of different technologies run at said fabricator;
 - a user interface adapted to receive user inputs for new design parameters and new critical gate dimensions associated with a new device to be produced at said fabricator; and
 - a computer adapted to:
 - receive said user inputs;
 - perform a regression analysis using said historical critical gate dimensions as independent variables and said historical costs as dependent variables, wherein said regression analysis produces relationship curves that only show relationships between said historical critical gate dimensions and said historical costs; and
 - calculate product costs of said new device based on said user inputs and said relationship curves.
2. (Currently Amended) The system in claim 1, all the limitations of which are incorporated herein by reference, wherein said historical critical gate dimensions and said new critical gate dimensions comprise gate dimensions.
3. (Currently Amended) The system in claim 1, all the limitations of which are incorporated herein by reference, wherein said new critical gate dimensions are smaller than said historical critical gate dimensions.

4. (Currently Amended) The system in claim 1, all the limitations of which are incorporated herein by reference, wherein said new device comprises a technology generation that is yet to be developed.

5. (Currently Amended) The system in claim 4, all the limitations of which are incorporated herein by reference, wherein fabrication hardware and fabrication methods for producing said technology generation are unknown.

6. (Cancelled).

7. (Currently Amended) The system in claim 1, all the limitations of which are incorporated herein by reference, wherein said relationship curves illustrate that costs increase exponentially as said historical critical gate dimensions and said historical critical ground rules are reduced.

8. (Previously Presented) A method of calculating semiconductor product costs comprising:
storing, in a database, historical costs and historical critical gate dimensions of different technologies run at a fabricator;
performing a regression analysis using said historical critical gate dimensions as independent variables and said historical costs as dependent variables, wherein said regression analysis produces relationship curves that show only relationships between said historical critical gate dimensions and said historical costs;
inputting new design parameters and new critical gate dimensions of a new device into said database; and
calculating product costs of said new device based on said relationship curves.

9. (Currently Amended) The method in claim 8, all the limitations of which are incorporated herein by reference, wherein said historical critical gate dimensions and said new critical gate dimensions comprise gate dimensions.

10. (Currently Amended) The method in claim 8, all the limitations of which are incorporated herein by reference, wherein said new critical gate dimensions are smaller than said historical critical gate dimensions.

11. (Currently Amended) The method in claim 8, all the limitations of which are incorporated herein by reference, wherein said new device comprises a technology generation that is yet to be developed.

12. (Currently Amended) The method in claim 11, all the limitations of which are incorporated herein by reference, wherein fabrication hardware and fabrication methods for producing said technology generation are unknown.

13. (Cancelled).

14. (Currently Amended) The method in claim 8, all the limitations of which are incorporated herein by reference, wherein said relationship curves illustrate that costs increase exponentially as said historical critical gate dimensions and said historical groundrules are reduced.

15. (Previously Presented) A system for calculating semiconductor product costs at a fabricator comprising:

- a regression analyzer adapted to produce relationship curves that show relationships between historical critical gate dimensions and historical costs of different technologies run at said fabricator;

- a user interface for inputting a new critical dimension of a new technology; and

- a calculator for calculating a cost of said new technology based only on said new critical gate dimension and said relationship curves.

16. (Currently Amended) The system in claim 15, all the limitations of which are incorporated herein by reference, wherein said historical critical gate dimensions and said new critical gate dimensions comprise gate dimensions.

17. (Currently Amended) The system in claim 15, all the limitations of which are incorporated herein by reference, wherein said new critical gate dimensions are smaller than said historical critical gate dimensions.

18. (Currently Amended) The system in claim 15, all the limitations of which are incorporated herein by reference, further comprising a storage unit adapted to store a database of said relationships.

19. (Currently Amended) The system in claim 15, all the limitations of which are incorporated herein by reference, wherein said new device comprises a technology generation that is yet to be developed.

20. (Currently Amended) The system in claim 19, all the limitations of which are incorporated herein by reference, wherein fabrication hardware and fabrication methods for producing said technology generation are unknown.

21. (Previously Presented) A computer program product stored a storage device readable by a computer, wherein said computer program product comprises a computer program for performing a method of calculating semiconductor product costs, said method comprising:
storing, in a database, historical costs and historical critical gate dimensions of different technologies run at a fabricator;

performing a regression analysis using said historical critical gate dimensions as independent variables and said historical costs as dependent variables, wherein said regression analysis produces relationship curves that only show relationships between said historical critical gate dimensions and said historical costs;

inputting new design parameters and new critical gate dimensions of a new device into said database; and

calculating product costs of said new device based on said relationship curves.

22. (Currently Amended) The computer program product in claim 21, all the limitations of which are incorporated herein by reference, wherein said historical critical gate dimensions and said new critical gate dimensions comprise gate dimensions.

23. (Currently Amended) The computer program product in claim 21, all the limitations of which are incorporated herein by reference, wherein said new critical gate dimensions are smaller than said historical critical gate dimensions.

24. (Currently Amended) The computer program product in claim 21, all the limitations of which are incorporated herein by reference, wherein said new device comprises a technology generation that is yet to be developed.

25. (Currently Amended) The computer program product in claim 24, all the limitations of which are incorporated herein by reference, wherein fabrication hardware and fabrication computer program products for producing said technology generation are unknown.

26. (Cancelled).

27. (Currently Amended) The computer program product in claim 21, all the limitations of which are incorporated herein by reference, wherein said relationship curves illustrate that costs increase exponentially as said historical critical gate dimensions are reduced.